EAST SEARCH

7/27/05

L#	Hits	Search String	Databases
L2	26	6,044,209.pn. or 5,859,776.pn. or 5,883,808.pn. or 5,764,528.pn. or 5,838,581.pn. or 5,446,6	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L3	121	((integrated or digital) adj circuit$1) with noise with model$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L4	8878	((integrated or digital) adj circuit$1) with noise	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L5	314	4 and (noise with model$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L6	47	5 and (("resistor capacitor" or RC) with circuit$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L7	31	4 and (("resistor capacitor" or RC) with circuit$1 with type$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L8	31	5 and (victim$1 with aggressor$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L9	26	5 and (coupling with aggressor$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L10	32	5 and (coupling with victim)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L11	90	5 and (noise with (peak or width))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L12	39	5 and (noise with width)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L13	106	5 and ("transition time" or "elmore delay" or "threshold voltage")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L14	69	5 and (coupling with (resistance or capacitance or location))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L16	36	13 and 14	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L17	39	11 and 12	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L18	18	5 and ("crosstalk noise")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L19	0	18 and (sink and source)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L20	0	18 and (receiver and transmitter)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L21	70	5 and ((sink and source) or (receiver and transmitter))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L23	0	5 and (lumped with capacitance$1 with weight$2)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L24	18	5 and (lumped with capacitance$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L25	16	24 and (path or branch)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L26	172	5 and ((("resistor capacitor" or RC) with circuit$1) or (victim$1 with aggressor$1) or (coupling	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L27	5	5 and (("resistor capacitor" or RC) with circuit$1 with pi)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L15	6	5 and ("RC delay")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L28	1	5 and (capacitance$1 with weight$2)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L29	2	26 and (noise with peak with threshold)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L30	8	26 and (noise with "pulse width")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L31	158	4 and (noise with "pulse width")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L32	0	31 and "elmore delay"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L33	8	4 and "pi model"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB

09/823085 Jason Cong

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Results of search set L26:5 and ((("resistor capacitor" or RC) with circuit$1) or (victim$1 with aggressor$1) or (coupling with aggressor$1) or ...

Document	Kind Codes	Title	Issue Date	Current OR	Abstract
US 20040103386	A1	Noise analysis for an integrated circuit model	20040527	716/13	
US 20040103381	A1	Semiconductor integrated circuit designing apparatus, semiconductor integrated circuit desigr	20040527	716/5	
US 20040087285	A1	VCO gain tracking for modulation gain setting calibration	20040506	455/126	
US 20040051511	A1	Method for delta-I noise reduction	20040318	323/283	
US 20040024554	A1	Method and apparatus for calibrating parameters to be used in a digital circuit simulation	20040205	702/107	
US 20040021599	A1	System and method for detecting an intruder using impulse radio technology	20040205	342/28	
US 20040019864	A1	METHOD AND APPARATUS FOR ANALYZING INDUCTIVE EFFECTS IN A CIRCUIT LAYC	20040129	716/6	
US 20040017224	A1	Integrated circuit and sensor for imaging	20040129	327/51	
US 20040013276	A1	Analog audio signal enhancement system using a noise suppression algorithm	20040122	381/94.3	
US 20030233622	A1	Method and apparatus for an asynchronous pulse logic circuit	20031218	716/1	
US 20030227032	A1	Wiring design method of integrated circuit device, system thereof, and program product there	20031211	257/208	
US 20030210101	A1	MEMS-based, computer systems, clock generation and oscillator circuits and LC-tank appara	20031113	331/117FE	
US 20030177427	A1	Circuit modeling	20030918	714/741	
US 20030176982	A1	Manufacturing integrated circuits and testing on-die power supplies using distributed program	20030918	702/60	
US 20030169121	A1	Method and apparatus to attenuate power plane noise on a printed circuit board using high E:	20030911	333/12	
US 20030163277	A1	Method for simulating power supply noise in an on-chip temperature sensor	20030828	702/136	
US 20030159121	A1	Variable stage ratio buffer insertion for noise optimization in a logic network	20030821	716/8	
US 20030155966	A1	Low-power, low-noise CMOS amplifier	20030821	330/9	
US 20030154454	A1	Method and system for estimating jitter in a delay locked loop	20030814	716/6	
US 20030154453	A1	Optimization of loop bandwidth for a phase locked loop	20030814	716/5	
US 20030154447	A1	Method for optimizing loop bandwidth in delay locked loops	20030814	716/2	
US 20030154065	A1	Method for optimizing decoupling capacitor design in delay locked loops	20030814	703/14	
US 20030154064	A1	Decoupling capacitor method for a phase locked loop	20030814	703/14	
US 20030154048	A1	Method for decoupling capacitor optimization for a temperature sensor design	20030814	702/132	
US 20030151464	A1	Jitter estimation for a phase locked loop	20030814	331/74	
US 20030138111	A1	Noise-suppressing receiver	20030724	381/71.7	
US 20030137877	A1	Noise reduction technique for transistors and small devices utilizing an episodic agitation	20030724	365/185.19	
US 20030128071	A1	Variable transconductance variable gain amplifier utilizing a degenerated differential pair	20030710	330/254	
US 20030115563	A1	Method for estimating peak crosstalk noise	20030619	716/5	
US 20030100040	A1	Blood analyte monitoring through subcutaneous measurement	20030529	435/14	
US 20030079191	A1	Cell-based noise characterization and evaluation	20030424	716/4	
US 20030030497	A1	Integrated VCO having an improved tuning range over process and temperature variations	20030213	331/34	
US 20030021440	A1	Digital watermarking employing noise model	20030130	382/100	
US 20030011424	A1	Simultaneous switching noise minimization technique for power lines using dual layer power li	20030116	327/565	
US 20020194573	A1	Method for simulating noise on the input of a static gate and determining noise on the output	20021219	716/5	
US 20020193959	A1	System and method of determining the noise sensitivity characterization for an unknown circu	20021219	702/117	
US 20020183054	A1	Mobile system testing architecture	20021205	455/423	
US 20020174409	A1	System and method for analyzing power distribution using static timing analysis	20021121	716/6	
US 20020174408	A1	System and method of determining the noise sensitivity of an integrated circuit	20021121	716/5	
US 20020147956	A1	Method for modeling noise emitted by digital circuits	20021010	716/4	

US 20020147555 A1	Method and apparatus for analyzing a source current waveform in a semiconductor integratec	20021010	702/70
US 20020147553 A1	Electromagnetic disturbance analysis method and apparatus and semiconductor device manu	20021010	702/65
US 20020130807 A1	System and method for detecting an intruder using impulse radio technology	20020919	342/28
US 20020121994 A1	Delta-sigma modulator system and method	20020905	341/143
US 20020050861 A1	Variable transconductance variable gain amplifier utilizing a degenerated differential pair	20020502	330/254
US 20020047942 A1	Digital IF demodulator for video applications	20020425	348/731
US 20020024407 A1	Distributed constant type noise filter	20020228	333/184
US 20020022951 A1	Method, apparatus and computer program product for determination of noise in mixed signal s	20020221	703/16
US 20010041548 A1	Variable gain amplifier for low voltage applications	20011115	455/252.1
US 20010025139 A1	Multivariate cardiac monitor	20010927	600/301
US 6751744 B1	Method of integrated circuit design checking using progressive individual network analysis	20040615	713/401
US 6750515 B2	SCR devices in silicon-on-insulator CMOS process for on-chip ESD protection	20040615	257/357
US 6748339 B2	Method for simulating power supply noise in an on-chip temperature sensor	20040608	702/136
US 6747501 B2	Dual-triggered electrostatic discharge protection circuit	20040608	327/310
US 6744320 B2	Variable transconductane variable gain amplifier utilizing a degenerated differential pair	20040601	330/254
US 6737887 B2	Current mode signal interconnects and CMOS amplifier	20040518	326/86
US 6732339 B2	Cell-based noise characterization and evaluation	20040504	716/4
US 6732336 B2	Method and apparatus for an asynchronous pulse logic circuit	20040504	716/1
US 6732065 B1	Noise estimation for coupled RC interconnects in deep submicron integrated circuits	20040504	703/2
US 6723577 B1	Method of forming an optical fiber interconnect through a semiconductor wafer	20040420	438/31
US 6718530 B2	Method and apparatus for analyzing inductive effects in a circuit layout	20040406	716/6
US 6704680 B2	Method for decoupling capacitor optimization for a temperature sensor design	20040309	702/130
US 6693439 B1	Apparatus and methods for measuring noise in a device	20040217	324/613
US 6691291 B2	Method and system for estimating jitter in a delay locked loop	20040210	716/6
US 6690065 B2	Substrate-biased silicon diode for electrostatic discharge protection and fabrication method	20040210	257/355
US 6687881 B2	Method for optimizing loop bandwidth in delay locked loops	20040203	716/2
US 6684065 B2	Variable gain amplifier for low voltage applications	20040127	455/252.1
US 6675365 B2	Method and system for predicting worst-case capacitive and inductive switching vector	20040106	716/6
US 6675118 B2	System and method of determining the noise sensitivity characterization for an unknown circu	20040106	702/117
US 6671863 B2	Optimization of loop bandwidth for a phase locked loop	20031230	716/6
US 6665845 B1	System and method for topology based noise estimation of submicron integrated circuit desig	20031216	716/5
US 6657566 B1	Conversion of a PCM signal into a UPWM signal	20031202	341/53
US 6653967 B2	Fully differential sampling circuit	20031125	341/172
US 6646523 B2	Distributed constant type noise filter	20031111	333/184
US 6633068 B2	Low-noise silicon controlled rectifier for electrostatic discharge protection	20031014	257/355
US 6617649 B2	Low substrate-noise electrostatic discharge protection circuits with bi-directional silicon diodes	20030909	257/355
US 6614384 B2	System and method for detecting an intruder using impulse radio technology	20030902	342/28
US 6611026 B2	Substrate-biased silicon diode for electrostatic discharge protection and fabrication method	20030826	257/355
US 6600243 B1	Battery pack and an information processing device in which the battery pack is detachable/att	20030729	307/150
US 6594805 B1	Integrated design system and method for reducing and avoiding crosstalk	20030715	716/5
US 6594630 B1	Voice-activated control for electrical device	20030715	704/256
US 6587815 B1	Windowing scheme for analyzing noise from multiple sources	20030701	703/13
US 6586835 B1	Compact system module with built-in thermoelectric cooling	20030701	257/717

US 6579690 B1	Blood analyte monitoring through subcutaneous measurement	20030617 435/14
US 6576974 B1	Bipolar junction transistors for on-chip electrostatic discharge protection and methods thereof	20030610 257/499
US 6570248 B1	Structure and method for a high-performance electronic packaging assembly	20030527 257/724
US 6567773 B1	Use of static noise analysis for integrated circuits fabricated in a silicon-on-insulator process t	20030520 703/14
US 6564355 B1	System and method for analyzing simultaneous switching noise	20030513 716/4
US 6556954 B1	Method and device for determining a fault in a technical system	20030429 702/185
US 6546529 B1	Method for performing coupling analysis	20030408 716/5
US 6539527 B2	System and method of determining the noise sensitivity of an integrated circuit	20030325 716/5
US 6536022 B1	Two pole coupling noise analysis model for submicron integrated circuit design verification	20030318 716/5
US 6526191 B1	Integrated circuits using optical fiber interconnects formed through a semiconductor wafer an	20030225 385/14
US 6523149 B1	Method and system to improve noise analysis performance of electrical circuits	20030218 716/4
US 6509796 B2	Variable transconductance variable gain amplifier utilizing a degenerated differential pair	20030121 330/254
US 6507935 B1	Method of analyzing crosstalk in a digital logic integrated circuit	20030114 716/5
US 6502223 B1	Method for simulating noise on the input of a static gate and determining noise on the output	20021231 716/5
US 6499131 B1	Method for verification of crosstalk noise in a CMOS design	20021224 716/5
US 6496370 B2	Structure and method for an electronic assembly	20021217 361/699
US 6493853 B1	Cell-based noise characterization and evaluation	20021210 716/5
US 6493395 B1	Multi-carrier transmission systems	20021210 375/261
US 6480998 B1	Iterative, noise-sensitive method of routing semiconductor nets using a delay noise threshold	20021112 716/13
US 6466629 B1	Multi-carrier transmission systems	20021015 375/316
US 6456649 B1	Multi-carrier transmission systems	20020924 375/222
US 6449753 B1	Hierarchical coupling noise analysis for submicron integrated circuit designs	20020910 716/5
US 6438174 B1	Multi-carrier transmission systems	20020820 375/261
US 6426680 B1	System and method for narrow band PLL tuning	20020730 331/34
US 6424034 B1	High performance packaging for microprocessors and DRAM chips which minimizes timing sk	20020723 257/723
US 6392296 B1	Silicon interposer with optical connections	20020521 257/698
US 6385565 B1	System and method for determining the desired decoupling components for power distributior	20020507 703/18
US 6378109 B1	Method of simulation for gate oxide integrity check on an entire IC	20020423 716/4
US 6363516 B1	Method for hierarchical parasitic extraction of a CMOS design	20020326 716/5
US 6363128 B1	Multi-carrier transmission systems	20020326 375/355
US 6281042 B1	Structure and method for a high performance electronic packaging assembly	20010828 438/108
US 6272465 B1	Monolithic PC audio circuit	20010807 704/258
US 6246774 B1	Wavetable audio synthesizer with multiple volume components and two modes of stereo posi	20010612 381/104
US 6219237 B1	Structure and method for an electronic assembly	20010417 361/699
US 6188344 B1	Signal processors	20010213 341/143
US 6177665 B1	High-speed logarithmic photo-detector	20010123 250/207
US 6150188 A	Integrated circuits using optical fiber interconnects formed through a semiconductor wafer an	20001121 438/31
US 6144217 A	Low switching noise logic circuit	20001107 326/27
US 6117182 A	Optimum buffer placement for noise avoidance	20000912 716/8
US 6104588 A	Low noise electrostatic discharge protection circuit for mixed signal CMOS integrated circuits	20000815 361/111
US 6090636 A	Integrated circuits using optical waveguide interconnects formed through a semiconductor wa	20000718 438/31
US 6073259 A	Low cost CMOS tester with high channel density	20000606 714/724
US 6072947 A	Method of making an integrated circuit including noise modeling and prediction	20000606 703/14

US 6064743 A	Wavetable audio synthesizer with waveform volume control for eliminating zipper noise	20000516	381/104
US 6058066 A	Enhanced register array accessible by both a system microprocessor and a wavetable audio :	20000502	365/230.05
US 6052316 A	Output buffer circuitry for semiconductor integrated circuit device	20000418	365/189.05
US 6047073 A	Digital wavetable audio synthesizer with delay-based effects processing	20000404	381/61
US 6041169 A	Method and apparatus for performing integrated circuit timing including noise	20000321	716/6
US 6029117 A	coupled noise estimation method for on-chip interconnects	20000222	702/58
US 6026286 A	RF amplifier, RF mixer and RF receiver	20000215	455/327
US 6002860 A	High frequency noise and impedance matched integrated circuits	19991214	703/14
US 6002122 A	High-speed logarithmic photo-detector	19991214	250/207
US 5926060 A	Mirror model for designing a continuous-time filter with reduced filter noise	19990720	327/538
US 5809466 A	Audio processing chip with external serial port	19980915	704/258
US 5799111 A	Apparatus and methods for smoothing images	19980825	382/254
US 5789799 A	High frequency noise and impedance matched integrated circuits	19980804	257/578
US 5760634 A	High speed, low noise output buffer	19980602	327/391
US 5742695 A	Wavetable audio synthesizer with waveform volume control for eliminating zipper noise	19980421	381/104
US 5731674 A	Motor with variable edge steepness	19980324	318/439
US 5691724 A	Police traffic radar using FFT processing to find fastest target	19971125	342/104
US 5682336 A	Simulation of noise behavior of non-linear circuit	19971028	703/3
US 5675808 A	Power control of circuit modules within an integrated circuit	19971007	713/322
US 5668507 A	Noise generator for evaluating mixed signal integrated circuits	19970916	331/78
US 5668338 A	Wavetable audio synthesizer with low frequency oscillators for tremolo and vibrato effects	19970916	84/629
US 5659466 A	Monolithic PC audio circuit with enhanced digital wavetable audio synthesizer	19970819	700/94
US 5570093 A	Police traffic radar using absolute signal strength information to improve target signal process	19961029	342/104
US 5568395 A	Modeling and estimating crosstalk noise and detecting false logic	19961022	716/4
US 5565871 A	Police traffic radar for allowing manual rejection of incorrect patrol speed display	19961015	342/176
US 5563603 A	Police traffic radar using digital data transfer between antenna and counting unit	19961008	342/115
US 5528245 A	Police traffic radar using double balanced mixer for even order harmonic suppression	19960618	342/104
US 5525996 A	Police traffic radar for calculating and simultaneously displaying fastest target speed	19960611	342/104
US 5517130 A	Method and structure for reducing noise in output buffer circuits	19960514	326/27
US 5481484 A	Mixed mode simulation method and simulator	19960102	703/14
US 5453693 A	Logging system for measuring dielectric properties of fluids in a cased well using multiple min	19950926	324/324
US 5274591 A	Serial clock noise immunity in a semiconductor memory integrated circuit having a serial port	19931228	365/189.05
US 5151612 A	Circuit for eliminating digital noise or short pulses utilizing set/reset shift register	19920929	327/34
US 5091699 A	Frequency division network having low phase noise	19920225	327/117
US 5084868 A	Common bus multinode sensor system	19920128	370/482
US 5027089 A	High frequency noise bypassing	19910625	333/12
US 4933973 A	Apparatus and methods for the selective addition of noise to templates employed in automatic	19900612	704/233
US 4847903 A	Wireless remote speaker system	19890711	381/3
US 4827427 A	Instantaneous incremental compiler for producing logic circuit designs	19890502	703/14
US 4770842 A	Common bus multinode sensor system	19880913	376/216
US 4577071 A	Echo canceller with adaptive residual center clipper controlled by echo estimate	19860318	379/406.08
US 4416024 A	Distortion reducing circuit in FM receiver	19831115	455/303
US 3911296 A	Capacitance multiplier circuit	19751007	327/552

US 6523149 B	Noise analysis method for electrical circuit, involves partitioning original multi-port circuit into r	20030218
US 6327542 B	Node coupling voltage noise approximation method for evaluating netlist file uses resistance,	20011204
US 6117182 A	Noise-reducing buffer insertion method for integrated circuit, involves modeling a data repres	20000912